

VIA EFS

**IN THE UNITED STATES PATENT AND TRADEMARK OFFICE**

In Re Patent Application:	Luca Pusterla, et al.	§	
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Conf. No.:	7623	§	Group Art Unit: 1743
		§	
Appln. No.:	10/601,383	§	Examiner: Yelena G Gakh
		§	
Filing Date:	June 23, 2003	§	Att'y. Docket No.: 6023-169US
		§	(BX2453M)
Title:	METHOD FOR MEASURING THE CONCENTRATION OF IMPURITIES IN HELIUM BY ION MOBILITY SPECTROMETRY		

**RESPONSE TO ELECTION OF SPECIES REQUIREMENT**

This is in response to the Office Action (Election of Species requirement) dated August 22, 2006 (Paper No. 20060817). This response is being timely submitted by September 22, 2006.